

BUREAU OF INDIAN STANDARDS

Program of Work

LITD 5 : Semiconductor And Other Electronic Components And Devices

Scope: To prepare Indian standards relating to: a) Semiconductor devices & integrated circuits. b) Capacitors, resistors, allied component c) Discrete semiconductor devices & micro-electromechanical systems d) Electronic assembly technologies and printed board assemblies. e) Capacitors resistors and inductors for use in electronics equipment.

Liaison: **IEC TC-40 (P):** *Capacitors and resistors for electronic equipment* **IEC TC-47 (O):** *Semiconductor devices* **IEC TC-47 SC-47A (O):** *Integrated circuits* **IEC TC-91 (P):** *Electronics assembly technology* **IEC TC-91 (P):** *Requirements for electronic components* **IEC TC-91 (P):** *Requirements for electronics assemblies* **IEC TC-91 (P):** *Measuring and test methods for electronics assemblies* **IEC TC-91 (P):** *Printed boards and materials* **IEC TC-91 (P):** *Vocabulary* **IEC TC-91 (P):** *Measuring and test methods for circuit boards and circuit board materials* **IEC TC-91 (P):** *Design methodology and data transfer of circuit boards and circuit board assemblies*

Published Standards

S.No	IS No.	TITLE	Reaffirm M-Y	No. of Amds	Eqv.
1	IS/QC 001001:2000 Reviewed In : 2024 IECQC 001001	IEC quality assessment system for electronic components (IECQ) - Basic rules (First Revision)	March, 2024	-	Identical under single numbering
2	IS/QC 001002-1:2000 Reviewed In : 2024 IECQC 001002-1:1998	IEC quality assessment system for electronic components (IECQ) - Rules of procedure: Part 1 administration (First Revision)	March, 2024	-	Identical under single numbering
3	IS/QC 001002-2:2000 Reviewed In : 2024 IECQC 001002-2: 1998	IEC quality assessment system for electronic components (IECQ) - Rules of procedure: Part 2 Documentation (First Revision)	March, 2024	-	Identical under single numbering
4	IS/QC 001002-3:2000 Reviewed In : 2024 IEC QC 001002-3 :1998	IEC quality assessment system for electronic components (IECQ) - Rules of procedure: Part 3 approval procedures (First Revision)	March, 2024	-	Identical under single numbering
5	IS/QC 001003:2000 Reviewed In : 2024 IECQC 001003	IEC quality assessment system for electronic components (IECQ) - Guidance documents	March, 2024	-	Identical under single numbering
6	IS 10249 (Part 1):1982 Reviewed In : 2021	Specification for voltage dependent resistors (Varistors): Part 1 general requirements and methods of tests	December, 2021	-	Indigenous
7	IS 11392 (Part 1/Sec 2):1988 Reviewed In : 2023	Dimensions of mounting accessories of pot cores for printed circuit board mountings: Part 1 for	February, 2023	-	Indigenous

		pot core of size 18 x 11 mm: Sec 2 type 2			
8	IS 11534 (Part 1):1985 Reviewed In : 2021 IEC 60738-1 :1982	Specification for directly heated positive step - Function temperature coefficient thermistors: Part 1 general requirements and methods of tests	December, 2021	-	Modified/Technically Equivalent
9	IS 12970 (Part 1):2010 Reviewed In : 2021 IEC 60748-1:2002	Semiconductor devices integrated circuits: Part 1 general	December, 2021	-	Identical under dual numbering
10	IS 12970 (Part 2):2021 IEC 60748-2: 1997 Reviewed In : 2024 IEC 60748-2: 1997	Semiconductor devices - Integrated circuits : Part 2 Digital integrated circuits essential ratings and characteristics Sec 1 General	March, 2024	-	Identical under dual numbering
11	IS 12970 (Part 3):2021 IEC 60748-3: 1994 IEC 60748-3: 1994	Semiconductor devices Integrated circuits Part 3 Analogue integrated circuits Superseding 1 IS 12970Part 5Sec 1:1991 2 IS 12970Part 5Sec 2:1992 3 IS 12970Part 5Sec 3:1992 4 IS 12970Part 5Sec 4:1992 5 IS 12970Part 5Sec 5:1993 6 IS 12970Part 5Sec		-	Identical under dual numbering
12	IS 13247 (Part 1):2021 IEC 60939-1: 2010 IEC 60939-1: 2010	Passive filter units for electromagnetic interference suppression Part 1 Generic specification First Revision and Superseding 1 IS 3723Part 1:1978 2 IS 3723Part 2:1983 and 3 IS 3723Part 3:1983		-	Identical under dual numbering
13	IS 13247 (Part 2):2021 IEC 60939-2:2005 IEC 60939-2:2005	Passive filter units for electromagnetic interference suppression Part 2 Sectional specification Passive filter units for which safety tests are appropriate Test methods and general requirements First Revision of IS 13247 Part 2		-	Identical under dual numbering
14	IS 13554:2020 IEC 60294 : 2012 IEC 60294 : 2012	Measurement of the Dimensions of a Cylindrical Component with Axial Terminations (First Revision)	-	-	Identical under dual numbering
15	IS 13562:1992 Reviewed In : 2021 IEC 60824	Terminology related to microprocessors	December, 2021	-	Modified/Technically Equivalent
16	IS 14901 (Part 1):2010 IEC 60747-1: 2006 Reviewed In : 2022 IEC 60747-1: 2006	Semiconductor devices - Discrete devices and integrated circuits: Part 1 general (First Revision)	February, 2022	-	Identical under dual numbering
17	IS 14901 (Part 2):2020 IEC 60747-2: 2016 IEC 60747-2 : 2016	Semiconductor Devices Part 2 Discrete Devices — Rectifier Diodes (First Revision)	-	-	Identical under dual numbering
18	IS 14901 (Part 3):2016 IEC 60747-3 : 2013	Semiconductor Devices Discrete Devices Part 3 Signal, Switching and Regulator Diodes	August, 2022	-	Identical under dual numbering

	Reviewed In : 2022 IEC 60747-3				
19	IS 14901 (Part 5):2004 IEC 60747-5 Reviewed In : 2021 IEC 60747-5:1992	Semiconductor devices - Discrete devices and integrated circuits: Part 5 optoelectronic devices	December, 2021	2	Identical under dual numbering
20	IS 14901 (Part 7):2020 IEC 60747-7 : 2010 IEC 60747-7 : 2010	Semiconductor Devices — Discrete Devices Part 7 Bipolar Transistors (First Revision)	-	-	Identical under dual numbering
21	IS 14901 (Part 8):2020 IEC 60747-8 : 2010 IEC 60747-8 : 2010	Semiconductor Devices — Discrete Devices Part 8 Field-Effect Transistors (Second Revision)	-	-	Identical under dual numbering
22	IS 15866 (Part 1):2010 IEC 60938-1:2006 Reviewed In : 2021 IEC 60938-1:2006	Fixed inductors for electromagnetic interference suppression: Part 1 generic specification	December, 2021	-	Identical under dual numbering
23	IS/QC 300000:1988 Reviewed In : 2021 IECQC 300000:1982	Fixed capacitors for use in electronic equipment generic specification	March, 2021	-	Identical under single numbering
24	IS/QC 300100:1988 Reviewed In : 2021 IECQC 300100: 1982	Fixed capacitors for use in electronic equipment: Sectional specification: fixed polyethersylen - Terephthalate film dielectric metal foil DC capacitor	March, 2021	-	Identical under single numbering
25	IS/QC 300201:2000 Reviewed In : 2021 IECQC 300201: 1984	Fixed capacitors for use in electronic equipment: Part 15 blank detail specification: fixed tantalum capacitors with solid electrolyte and porous anode assessment level E	March, 2021	1	Identical under single numbering
26	IS/QC 300301:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 300301: 1985	Fixed capacitors for use in electronic equipment blank detail specification aluminium electrolytic capacitors with non - Solid electrolyte assessment level E	March, 2021	-	Identical under single numbering
27	IS/QC 300401:1988 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 300401: 1982	Fixed capacitors for use in electronic equipment blank detail specification fixed metallized polyethylene - Terephthalate film dielectric D C capacitors assessment level e	March, 2021	-	Identical under single numbering
28	IS/QC 300600:1993 Reviewed In : 2021 IECQC 300600: 1988	Fixed capacitors for use in electronic equipment - Sectional specification for fixed capacitors of ceramic dielectric, class 1	March, 2021	-	Identical under single numbering
29	IS/QC 300601:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 300601: 1988	Fixed capacitors for use in electronic equipment,blank detail specification for fixed capacitors of ceramic dielectric,class 1,assessment level E	March, 2021	-	Identical under single numbering
30	IS/QC 300701:1993 Reviewed In : 2021 Reaffirmed but not	Fixed Capacitors for Use in Electronic Equipment Sectional Fixed Capacitors of Ceramic	March, 2021	-	Identical under single numbering

	taken up for revision IECQC 300701: 1988	Dielectric, Class 2			
31	IS/QC 300800:1994 Reviewed In : 2020 IECQC 300800: 1989	Fixed capacitors for use in electronic equipment: Sectional specification for fixed tantalum chip capacitors	September, 2020	-	Identical under single numbering
32	IS/QC 300801:1993 Reviewed In : 2020 Reaffirmed but not taken up for revision IECQC 300801	Fixed capacitors for use in electronic equipment blank detail specification for fixed tantalum chip capacitors assessment level E	September, 2020	-	Identical under single numbering
33	IS/QC 301200:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 301200: 1982	Fixed capacitors for use in electronic equipment Sectional specification for fixed metallized polypropylene film dielectric D.C. capacitors	March, 2021	-	Identical under single numbering
34	IS/QC 301201:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 301201: 1982	Fixed capacitors for use in electronic equipment - Blank detail specification for fixed metallized polypropylene film dielectric D. C. capacitors - Assessment level e	March, 2021	-	Identical under single numbering
35	IS/QC 301301:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 301301: 1987	Fixed capacitors for use in electronic equipment, blank detail specification for fixed metallized polypropylene film dielectric A.C. and pulse capacitors,assessment level E	March, 2021	-	Identical under single numbering
36	IS/QC 301800:2001 Reviewed In : 2020 IECQC 301800: 1991	Fixed capacitors for use in electronic equipment: Part 13 Secal specification fixed polypropylene film dielectric metal foil D.C. capacitors: Sec one - General	September, 2020	-	Identical under single numbering
37	IS/QC 301801:2001 Reviewed In : 2020 IECQC 301801: 1991	Fixed capacitors for use in electronic equipment: Part 13 blank detail specification fixed polypropylene film dielectric metal foil D.C. capacitors assessment level E	September, 2020	-	Identical under single numbering
38	IS/QC 302400:1994 Reviewed In : 2018 IECQC 302400: 1993	Fixed capacitors for use in electronic equipment: Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains	March, 2018	-	Identical under single numbering
39	IS/QC 400100:1988 Reviewed In : 2021 IECQC 400100: 1982	Fixed resistors for use in electronic equipment: Sectional specification fixed low - Power non - Wire wound resistors	March, 2021	-	Identical under single numbering
40	IS/QC 400101:1988 Reviewed In : 2021 IECQC 400101: 1982	Fixed resistors for use in electronic equipment blank detail specification fixed low - Power non - Wirewound resistors assessment level E	March, 2021	-	Identical under single numbering
41	IS/QC 400200:1992 Reviewed In : 2021 IECQC 400200:	Fixed resistors for use in electronic equipment: Sectional specification: fixed power resistors	March, 2021	-	Identical under single numbering

	1982				
42	IS/QC 400400:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400400: 1983	Fixed resistors for use in electronic equipment - Sectional specification for fixed resistor networks with individually measurable resistors	March, 2021	-	Identical under single numbering
43	IS/QC 400401:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400401: 1983	Fixed resistors for use in electronic equipment - Blank detail specification - Fixed resistor networks with individually measurable resistors, all of equal value and equal dissipation assessment level E	March, 2021	-	Identical under single numbering
44	IS/QC 400500:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400500: 1984	Fixed resistors for use in electronic equipment - Sectional specification for fixed resistor networks in which not all resistors are individually measurable	March, 2021	-	Identical under single numbering
45	IS/QC 400501:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400501: 1984	Fixed resistors for use in electronic equipment - Blank detail specification for fixed resistors networks in which not all resistors are individually measurable - Assessment level E	March, 2021	-	Identical under single numbering
46	IS/QC 400600:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400600: 1989	Fixed resistors for use in electronic equipment: Sectional specification for fixed chip resistors	March, 2021	-	Identical under single numbering
47	IS/QC 400601:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400601: 1989	Fixed resistors for use in electronic equipment blank detail specification for fixed chip resistors assessment level E	March, 2021	-	Identical under single numbering
48	IS/QC 410100:1992 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 410100: 1989	Potentiometers for use in electronic equipment Sectional specification lead - Screw actuated and rotary preset potentiometers	March, 2021	-	Identical under single numbering
49	IS/QC 410101:1992 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 410101	Potentiometers for Use in Electronic Equipment Blank Detail Specification: Lead-Screw Actuated and Rotary Preset Potentiometers Assessment Level E	March, 2021	-	Identical under single numbering
50	IS/QC 420000:1994 Reviewed In : 2023 IECQC 420000	Varistors for use in electronic equipment - Generic specification	November, 2023	-	Identical under single numbering
51	IS/QC 420100:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 420100	Varistors for use in electronic equipment. -Sectional specification for surge suppression varistors	March, 2021	-	Identical under single numbering
52	IS/QC 420102:1993	Varistors for use in electronic	March, 2021	-	Identical under single

	Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 420102	equipment - Blank detail specification for zinc oxide surge suppression varistors - Assessment level E			numbering
53	IS/QC 440000:1994 Reviewed In : 2018 IECQC 440000	Directly heated positive step function temperature coefficient thermistors - Generic specification	March, 2018	-	Identical under single numbering
54	IS/QC 440001:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 440001	Directly heated positive step function temperature coefficient thermistors - Blank detail specification - Assessment level E	March, 2021	-	Identical under single numbering
55	IS 5001:2018 IEC 60191-1 : 2007 Reviewed In : 2021 IEC 60191-1:2007	Mechanical standardization of semiconductor devices - General rules for the preparation of outline drawings of discrete devices (First Revision)	March, 2021	-	Identical under dual numbering
56	IS 5001 (Part 1):1969 Reviewed In : 2021 IEC 60191 - 1 : 1966	Guide for Preparation of Drawings of Semiconductor Devices	March, 2021	1	Modified/Technically Equivalent
57	IS/IEC 60068-2-20):2021 IEC 60068-2-20: 2021 IEC 60068-2-20: 2021	Environmental testing Part 2 Tests Section 20 Tests Ta and Tb: Test methods for solderability and resistance to soldering heat of devices with leads		-	Identical under single numbering
58	IS/IEC 60068-2-21):2021 IEC 60068-2-21:2021 IEC 60068-2-21:2021	Environmental Testing Part 2: Tests Section 21: Test U: Robustness of Terminations and Integral Mounting Devices Superseding IS 9000 Part 19Section 1 to 5:1986		-	Identical under single numbering
59	IS/IEC 60068-2-58):2015 IEC 60068-2-58: 2015	Environmental testing Part 2 Tests Section 58 Test Td: Test methods for solderability resistance to dissolution of metallization and to soldering heat of surface mounting devicesSMD		-	
60	IS/IEC 60068-2-69):2017 IEC 60068-2-69 : 201 IEC 60068-2-69 : 201	Environmental testing Part 2 Tests Section 69 Test TeTc: Solderability testing of electronic components and printed boards by the wetting balance force measurement method		-	Identical under single numbering
61	IS/IEC 60068-2-82):2019 IEC 60068-2-82: 2019	Environmental testing Part 2 Tests Section 82 Test Xw1: Whisker test methods for components and parts used in electronic assemblies		-	
62	IS/IEC 60068-2-83):2011 IEC 60068-2-83: 2011 IEC 60068-2-83: 2011	Environmental testing Part 2 Tests Section 83 Test Tf: Solderability testing of electronic components for surface mounting devices SMD by the wetting balance method using solder paste		-	Identical under single numbering
63	IS/IEC 60115-1:2020 IEC 60115-1: 2020	Fixed resistors for use in electronic equipment Part 1 Generic specification		-	Identical under single numbering

	IEC 60115-1: 2020				
64	IS/IEC 60115-2:2023 IEC 60115-2: 2023 IEC 60115-2: 2023	Fixed resistors for use in electronic equipment Part 2 Sectional specification: Low-power film resistors with leads for through-hole assembly on circuit boards (THT)		-	Identical under single numbering
65	IS/IEC 60194:2015 IEC 60194 : 2015 Reviewed In : 2021 IEC 60194 : 2015	Printed Board Design Manufacture and Assembly-Terms and Definitions	March, 2021	-	Identical under dual numbering
66	IS/IEC 60195:2016 IEC 60195:2016 IEC 60195:2016	Method of measurement of current noise generated in fixed resistors Superseding IS 5027 : 1969		-	Identical under single numbering
67	IS/IEC 60384-4:2016 IEC 60384-4: 2016 IEC 60384-4: 2016	Fixed capacitors for use in electronic equipment Part 4 Sectional specification Fixed aluminium electrolytic capacitors with solid MnO ₂ and non-solid electrolyte Superseding IS 4317: 1983 and ISQC 300300 : 1992		-	Identical under single numbering
68	IS/IEC 60384-9:2015 IEC 60384-9: 2015 IEC 60384-9: 2015	Fixed capacitors for use in electronic equipment Part 9: Sectional specification: Fixed capacitors of ceramic dielectric Class 2 Superseding IS 2786 Part 1: 1978 and ISQC 300700: 1994		-	Identical under single numbering
69	IS/IEC 60384-15:2017 IEC 60384-15: 2017 IEC 60384-15: 2017	Fixed capacitors for use in electronic equipment Part 15 Sectional specification: Fixed tantalum capacitors with non-solid or solid electrolyte		-	Identical under single numbering
70	IS/IEC 60384-141-1):2016 IEC 60384-14-1: 2016 IEC 60384-14-1: 2016	Fixed capacitors for use in electronic equipment Part 14 Blank detail specification Fixed capacitors for electromagnetic interference suppression and connection to the supply mains Section 1 Assessment level DZ Superseding ISQC 302401 : 1994		-	Identical under single numbering
71	IS/IEC 60440:2012 IEC 60440 : 2012 IEC 60440 : 2012	Method of measurement of non-linearity in resistors		-	Identical under single numbering
72	IS/IEC 61189-1:2001 IEC 61189-1: 2001 IEC 61189-1: 2001	Test methods for electrical materials interconnection structures and assemblies Part 1 General test methods and methodology		-	Identical under single numbering
73	IS/IEC 61189-2:2006 IEC 61189-2:2006 IEC 61189-2:2006	Test methods for electrical materials printed boards and other interconnection structures and assemblies Part 2:Test methods for materials for interconnection structures		-	Identical under single numbering
74	IS/IEC 61189-3:2007 IEC 61189-3: 2007 IEC 61189-3: 2007	Test methods for electrical materials printed boards and other interconnection structures and assemblies Part 3 Test methods for interconnection structures printed boards		-	Identical under single numbering

75	IS/IEC 61189-5:2006 IEC 61189-5:2006 IEC 61189-5:2006	Test methods for electrical materials interconnection structures and assemblies Part 5 Test methods for printed board assemblies		-	Identical under single numbering
76	IS/IEC 62137-4:2014 62137-4: 2014 62137-4: 2014	Electronics assembly technology Part 4 Endurance test methods for solder joint of area array type package surface mount devices		-	Identical under single numbering
77	IS/IEC 62326-1:2002 IEC 62326-1 : 2002 Reviewed In : 2024 IEC 62326-1 : 2002	Printed Boards Part 1 Generic specification	March, 2024	-	Identical under dual numbering
78	IS/IEC 62326-20:2016 IEC 62326-20 : 2016 Reviewed In : 2024 IEC 62326-20 : 2016	Printed Boards Part 20 Printed Circuit Boards for High-Brightness LEDs	March, 2024	-	Identical under dual numbering
79	IS/IEC 62421:2007 IEC 62421 : 2007 Reviewed In : 2024 IEC 62421 : 2007	Electronics Assembly Technology- Electronic Modules	March, 2024	-	Identical under dual numbering
80	IS/IEC/TR 63091:2017 IEC TR 63091: 2017 IEC TR 63091: 2017	Study for the derating curve of surface mount fixed resistors Derating curves based on terminal part temperature		-	Identical under single numbering
81	IS 7305:2018 IEC 60384-1 : 2016 Reviewed In : 2021 IEC 60384-1:2016	Fixed capacitors for use in electronic equipment - Generic specification (Second Revision)	March, 2021	-	Identical under dual numbering
82	IS/QC 760000:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 760000	Semiconductor devices - Integrated circuits - Generic specification for film integrated circuits and hybrid film integrated circuits	March, 2021	-	Identical under single numbering
83	IS/QC 760100:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 760100	Semiconductor devices - Integrated circuits - Sectional specification for film integrated circuits and hybrid film integrated circuits on the basis of qualification approval procedure	March, 2021	-	Identical under single numbering
84	IS/QC 760101:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 760101	Semiconductor devices - Integrated circuits - Blank detail specification for film integrated circuits and hybrid film integrated circuits on the basis of qualification approval procedure	March, 2021	-	Identical under single numbering
85	IS/QC 760200:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 760200	Semiconductor devices - Integrated circuits - SectlOnal specification for film integrated circuits and hybrid film integrated circuits on the basis of the capability approval procedures	March, 2021	-	Identical under single numbering
86	IS/QC 760201:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision	Semiconductor devices - Integrated circuits - Blank detail specification for film integrated circuits and hybrid film integrated circuits on	March, 2021	-	Identical under single numbering

	IECQC 760201	the basis of the capability approval procedures			
87	IS/QC 790130:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 790130	Semiconductor devices - Integrated circuits - Digital integrated circuits - Blank detail specification for HCMOS digital integrated circuits (Series 54/74 HC, 54/74 HCT, 54/74 HCU)	March, 2021	-	Identical under single numbering
88	IS/QC 790131:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 790131	Semiconductor devices - Integrated circuits - Digital integrated circuits - Blank detail specification for complementary MOS digital integrated circuits (Series 4000 Band 4000 Ub)	March, 2021	-	Identical under single numbering
89	IS/QC 790132:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 790132	Semiconductor devices - Integrated circuits - Digital integrated circuits - Blank detail specification for bipolar monolithic digital integrated circuit gates (Excluding Uncommitted Logic Arrays)	March, 2021	-	Identical under single numbering
90	IS/QC 790202:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 790202	Semiconductor devices - Integrated circuits - Analogue integrated circuits blank detail specification for monolithic integrated operational amplifiers	March, 2021	-	Identical under single numbering
91	IS 8186:2020 IEC 60062 : 2016 IEC 60062 : 2016	Marking Codes for Resistors and Capacitors (First Revision)	-	-	Identical under dual numbering
92	IS 824:2021 IEC 60063: 2015 IEC 60063: 2015	Preferred number series for Resistors and Capacitors		-	Identical under dual numbering
93	IS 8872 (Part 1):2018 IEC 60393-1 : 2008 Reviewed In : 2021 IEC 60393-1:2008	Potentiometers for use in electronic equipment: Part 1 generic specification (First Revision)	November, 2021	-	Identical under dual numbering
94	IS 9000 (Part 19/Sec 15):1986 Reviewed In : 2022	Basic environmental testing procedures for electronic and electrical items: Part 19 test u: robustness of terminations and integral mounting devices (First Revision)	October, 2022	-	Indigenous
95	IS 9256 (Part 1):2019 IEC 60384-2 : 2011 Reviewed In : 2022 IEC 60384-2 :2011	Fixed capacitors for use in electronic equipment: Part 1 Sectional specification - Fixed metallized polyethylene terephthalate film dielectric d.c. capacitors (First Revision)	May, 2022	-	Identical under dual numbering
96	IS 9638 (Part 1):1980 Reviewed In : 2021	Specification for fixed polyester film dielectric capacitors for direct current: Part 1 general requirements and methods of tests	December, 2021	-	Indigenous

Standards under Development

Projects Approved

SI. No.	Doc No.	Title
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Preliminary Draft Standards

SI. No.	Doc No.	Title
No Records Found		

Drafts Standards in WC Stage

SI. No.	Doc No.	Title
No Records Found		

Draft Standards Completed WC Stage

SI. No.	Doc No.	Title
No Records Found		

Finalized Draft Indian Standard

SI. No.	Doc No.	Title
1	LITD 5 (23252)	Fixed resistors for use in electronic equipment Part 2 Blank detail specification Section 10 Low-power film resistors with leads for through-hole assembly on circuit boards THT for general electronic equipment classification level G
2	LITD 5 (23253)	Fixed resistors for use in electronic equipment Part 4 Sectional specification Power resistors for through hole assembly on circuit boards THT or for assembly on chassis Superseding ISQC 400200 1992
3	LITD 5 (23254)	Fixed Capacitors for use in Electronic Equipment Part 1 Generic Specification
4	LITD 5 (23255)	Fixed Capacitors for use in Electronic Equipment Part 1 Generic Specification Section 1 Blank Detail Specification
5	LITD 5 (23256)	Fixed Capacitors for use in Electronic Equipment Part 2 Sectional Specification - Fixed Metallized Polyethylene Terephthalate Film Dielectric DC Capacitors
6	LITD 5 (23257)	Fixed Capacitors for use in Electronic Equipment Part 14 Sectional Specification - Fixed Capacitors for Electromagnetic Interference Suppression and Connection to the Supply Mains Superseding ISQC 302400 1994
7	LITD 5 (23258)	Thermistors Directly heated positive temperature coefficient Part 1 Generic specification
8	LITD 5 (23274)	Semiconductor Devices Discrete Devices Part 8 Field-Effect Transistors Second Revision Amendment - 1

Finalized Draft Indian Standards under Print

SI. No.	Doc No.	Title
1	LITD 5 (03384)	Semiconductor Devices - Part 4 Microwave diodes and transistors
2	LITD 5 (03383)	Semiconductor Devices - Part 3 Discrete Devices - Signal Switching and Regulator Diodes
3	LITD 5 (10475) Amendment of: IS 7305:2018	Fixed capacitors for use in electronic equipment Generic specification
4	LITD 5 (10477) Amendment of: IS 5786:2018	Fixed resistors for use in electronic equipment Part 1 Generic specification
5	LITD 5 (10478) Amendment of: IS 5001:1969	Mechanical standardization of semiconductor devices Part 1 General rules for the preparation of outline drawings of discrete devices
6	LITD 5 (10479) Amendment of: IS 8872:2018	Potentiometers for use in electronic equipment Part 1 Generic specification
7	LITD 5 (10480) Amendment of: IS 9256:2019	Fixed capacitors for use in electronic equipment Part 2 Sectional specification Fixed metallized polyethylene terephthalate film dielectric dc capacitors

8	LITD 5 (10593)	Printed board design manufacture and assembly Terms and definitions
9	LITD 5 (10594)	Printed boards Part 1 Generic specification
10	LITD 5 (10595)	Printed boards Part 20 Printed circuit boards for high-brightness LEDs
11	LITD 5 (10596)	Electronics assembly technology - Electronic modules
12	LITD 5 (12219) Amendment of: IS 8186:2020	MARKING CODES FOR RESISTORS AND CAPACITORS
13	LITD 5 (12220) Amendment of: IS 13554:2020	Measurement of the dimensions of a cylindrical component with axial terminations
14	LITD 5 (12221) Amendment of: IS 14901:2020	SEMICONDUCTOR DEVICES Part 2 Discrete devices Rectifier diodes
15	LITD 5 (12223) Amendment of: IS 14901:2020	SEMICONDUCTOR DEVICES DISCRETE DEVICES Part 7 Bipolar transistors
16	LITD 5 (12224) Amendment of: IS 14901:2020	Semiconductor devices Discrete devices Part 8 Field-effect transistors
17	LITD 5 (14706) Amendment of: IS 824:1965	Preferred number series for Resistors and Capacitors
18	LITD 5 (14707) Amendment of: IS 13247:1992	Passive filter units for electromagnetic interference suppression Part 1 Generic specification First Revision and Superseding 1 IS 3723Part 1 1978 2 IS 3723Part 2 1983 and 3 IS 3723Part 3 1983
19	LITD 5 (14708) Amendment of: IS 13247:1992	Passive filter units for electromagnetic interference suppression Part 2 Sectional specification Passive filter units for which safety tests are appropriate Test methods and general requirements First Revision of IS 13247 Part 2
20	LITD 5 (14709) Amendment of: IS 12970:1993	Semiconductor devices - Integrated circuits Part 2 Digital integrated circuits essential ratings and characteristics Sec 1 General
21	LITD 5 (14711) Amendment of: IS 12970:1991	Semiconductor devices Integrated circuits Part 3 Analogue integrated circuits Superseding 1 IS 12970Part 5Sec 1 1991 2 IS 12970Part 5Sec 2 1992 3 IS 12970Part 5Sec 3 1992 4 IS 12970Part 5Sec 4 1992 5 IS 12970Part 5Sec 5 1993 6 IS 12970Part 5Sec
22	LITD 5 (16663)	Test methods for electrical materials interconnection structures and assemblies Part 1 General test methods and methodology
23	LITD 5 (16668)	Test methods for electrical materials printed boards and other interconnection structures and assemblies Part 3 Test methods for interconnection structures printed boards
24	LITD 5 (16669)	Test methods for electrical materials printed boards and other interconnection structures and assemblies Part 2 Test methods for materials for interconnection structures
25	LITD 5 (16671)	Test methods for electrical materials interconnection structures and assemblies Part 5 Test methods for printed board assemblies
26	LITD 5 (16954)	Environmental testing Part 2 Tests Section 58 Test Td Test methods for solderability resistance to dissolution of metallization and to soldering heat of surface mounting devicesSMD
27	LITD 5 (16955)	Environmental testing Part 2 Tests Section 69 Test TeTc Solderability testing of electronic components and printed boards by the wetting balance force measurement method
28	LITD 5 (16956)	Environmental testing Part 2 Tests Section 82 Test Xw1 Whisker test methods for components and parts used in electronic assemblies
29	LITD 5 (16957)	Environmental testing Part 2 Tests Section 83 Test Tf Solderability testing of electronic components for surface mounting devices SMD by the wetting balance method using solder paste
30	LITD 5 (16958)	Electronics assembly technology Part 4 Endurance test methods for solder joint of area array type package surface mount devices
31	LITD 5 (18108)	Study for the derating curve of surface mount fixed resistors Derating curves based on terminal part temperature
32	LITD 5 (18462)	Environmental testing Part 2 Tests Section 20 Tests Ta and Tb Test methods for solderability and resistance to soldering heat of devices with leads
33	LITD 5 (18463)	Fixed resistors for use in electronic equipment Part 1 Generic specification
34	LITD 5 (18464)	Method of measurement of current noise generated in fixed resistors Superseding IS 5027 1969
35	LITD 5 (18465)	Method of measurement of non-linearity in resistors

36	LITD 5 (18472)	Fixed capacitors for use in electronic equipment Part 4 Sectional specification Fixed aluminium electrolytic capacitors with solid MnO ₂ and non-solid electrolyte Superseding IS 4317 1983 and ISQC 300300 1992
37	LITD 5 (18473)	Fixed capacitors for use in electronic equipment Part 9 Sectional specification Fixed capacitors of ceramic dielectric Class 2 Superseding IS 2786 Part 1 1978 and ISQC 300700 1994
38	LITD 5 (18476)	Fixed capacitors for use in electronic equipment Part 14 Blank detail specification Fixed capacitors for electromagnetic interference suppression and connection to the supply mains Section 1 Assessment level DZ Superseding ISQC 302401 1994
39	LITD 5 (18477)	Fixed capacitors for use in electronic equipment Part 15 Sectional specification Fixed tantalum capacitors with non-solid or solid electrolyte
40	LITD 5 (23249)	Environmental Testing Part 2 Tests Section 21 Test U Robustness of Terminations and Integral Mounting Devices Superseding IS 9000 Part 19Section 1 to 5 1986
41	LITD 5 (23250)	Fixed resistors for use in electronic equipment Part 2 Sectional specification Low-power film resistors with leads for through-hole assembly on circuit boards THT
42	LITD 5 (23273)	Semiconductor Devices Discrete Devices Part 7 Bipolar Transistors First Revision Amendment - 1
43	LITD 5 (25416)	Varistors for use in Electronic Equipment Part 1 Generic Specification
44	LITD 5 (25417)	Fixed Capacitors for use in Electronic Equipment Part 11 Sectional Specification Fixed Polyethylene-Terephthalate Film Dielectric Metal Foil DC Capacitors
45	LITD 5 (25418)	Fixed Capacitors for use in Electronic Equipment Part 8 Sectional Specification Fixed Capacitors of Ceramic Dielectric Class 1
46	LITD 5 (25420)	Fixed Capacitors for use in Electronic Equipment Part 3 Sectional Specification Surface Mount Fixed Tantalum Electrolytic Capacitors with Solid MnO ₂ Electrolyte

Total Published Standards:93 Total Standards Under development:54

Aspect Wise Report

Product : 64
 Code of Practices : 9
 Methods of Test : 17
 Terminology : 3
 Dimensions : 1
 System Standard : 0
 Safety Standard : 0
 Others : 0
 Service Specification : 0
 Process Specification : 0
 Unclassified : 2

Annexure-I :List of Indian Standards Withdrawn/Superseded

SI. No.	IS No. & Year	Title
1	IS 10249 (Part 2/Sec 1):1983 Reviewed In : 2021	Specification for voltage dependent resistors Varistors Part 2 low voltage Sec 1 type VDF 1
2	IS 10249 (Part 2/Sec 2):1983 Reviewed In : 2021	Specification - for voltage dependent resistors Varistors Part 2 low voltage Sec 2 type VDS 1
3	IS 1031:1967	Methods of measurements on loudspeakers and loudspeaker systems
4	IS 1032:1957	General requirements end tests for pressure unit operated horn loudspeaker systems
5	IS 10320:1982 IEC 60701 Reviewed In : 2008	General requirements and tests for axial lead cores made of magnetic oxides or iron powder
6	IS 1033:1957	General requirement and tests for direct radiator moving coil loudspeaker
7	IS 1034:1957	Loudspeakers systems for community radio receivers

8	IS 10424:1982 Reviewed In : 2020 IEC 60326-3:	Guide for design and use of printed boards
9	IS 10477:1982 Reviewed In : 2023	Environmental testing procedures for microcircuits
10	IS 10825 (Part 1):1975 Reviewed In : 2021	Specification for ceramic dielectric capacitors type 1 Part 1 general requirements and methods of tests
11	IS 10825 (Part 2):1984 Reviewed In : 2021	Specification for ceramic dielectric capacitors type 1 Part 2 type FCCT - 1
12	IS 10825 (Part 3):1984 Reviewed In : 2021	Specification for ceramic capacitors type 1 Part 3 FCCT 2
13	IS 10991 (Part 1):1984 Reviewed In : 2021	Specification for fixed metallized polypropylene film dielectric capacitors Part 1 general requirements and methods of tests
14	IS 11214:1984 Reviewed In : 2020	Guide for repair of printed wiring boards and assemblies
15	IS 11392 (Part 1/Sec 1):1985 Reviewed In : 2023	Dimensions of mounting accessories of pot cores for printed circuit board mountings Part 1 - For pot cores of size 18 x 11 Mm Sec 1 type 1
16	IS 11515 (Part 1):1985 Reviewed In : 2018	Specification for fixed metallized polycarbonate film dielectric capacitors Part 1 general requirements and methods of tests
17	IS 11515 (Part 2):1986 Reviewed In : 2018	Specification for fixed metallised polycarbonate film dielectric capacitors Part 2 type FCCM 1
18	IS 11515 (Part 3):1986 Reviewed In : 2018	Specification for fixed metallised polycarbonate film dielectric capacitors Part 3 type FCCM 2
19	IS 12032 (Part 5):1993 IEC 617-5: 1983 Reviewed In : 2018 IEC 617-5: 1983	Graphical symbols for diagrams in the field of electrotechnology Part 5 semiconductors and electron tubes
20	IS 12032 (Part 12):1994 IEC 617-12: 1983 Reviewed In : 2018 IEC 617-12: 1983	Graphical symbols for diagrams in the field of electrotechnology Part 12 binary logic elements
21	IS 12032 (Part 13):1992 IEC 617-13: 1978 Reviewed In : 2018 IEC 617-13: 1978	Graphical symbols for diagrams in the field of electrotechnology Part 13 analogue elements
22	IS 12071:1987 Reviewed In : 2017	Guide for assembly of printed boards
23	IS 12284:1988 Reviewed In : 2020 IEC 60249-3-1: 1981	Specification for prepreg for reuse in multilayer printed boards
24	IS 12641:2004 IEC 60749: 2002 Reviewed In : 2018 IEC 60749: 2002	Semiconductor devices - Mechanical and climatic test methods First Revision
25	IS 12970 (Part 2/Sec 2):1992 Reviewed In : 2018	Semiconductor devicesintegrated circuits Part 2 digital integrated circuits - Essential ratings and characteristics Sec 2 integrated circuit memories
26	IS 12970 (Part 2/Sec 3):1993 Reviewed In : 2018	Semiconductor devices - Integrated circuits Part 2 digital integrated circuits - Essential rating and characteristics Sec 3 integrated circuit microprocessors
27	IS 12970 (Part 3/Sec 1):1992 Reviewed In : 2018	Semiconductor devices - Integrated circuits Part 3 digital integrated circuits - Measuring methods Sec 1 general
28	IS 12970 (Part 3/Sec 2):1992 Reviewed In : 2018	Semiconductor devices integrated circuits Part 3 digital integrated circuits - Measuring methods Sec 2 static characteristics
29	IS 12970 (Part 3/Sec	Semiconductor devices - Integrated circuits Part 3 digital integrated circuits - Measuring methods

	3):1993 Reviewed In : 2018	Sec 3 dynamic measurements
30	IS 12970 (Part 5/Sec 2):1992 Reviewed In : 2018	Semiconductor devices integrated circuits Part 5 analogue integrated circuits - Essential ratings and characteristics Sec 2 operational amplifiers
31	IS 12970 (Part 5/Sec 3):1992 Reviewed In : 2018	Semiconductor devices - Integrated circuits Part 5 analogue integrated circuits - Essential ratings and characteristics Sec 3 audio amplifiers video amplifiers and multichannel amplifiers for telecommunications
32	IS 12970 (Part 5/Sec 4):1992 Reviewed In : 2018	Semiconductor devices - Integrated circuits Part 5 analogue integrated circuits - essential ratings and characteristics Sec 4 R F and I F amplifiers
33	IS 12970 (Part 5/Sec 5):1993 Reviewed In : 2018	Semiconductor devices - Integrated circuits Part 5 analogue integrated circuits - Essential ratings and characteristics Sec 5 voltage and current regulators
34	IS 12970 (Part 5/Sec 6):1993 Reviewed In : 2018	Semiconductor devices - Integrated circuits Part 5 analogue INtegrated circuits - Essential ratings and characteristics Sec 6 analogue signal switching circuits
35	IS 12970 (Part 6/Sec 1):1992 Reviewed In : 2018	Semiconductor devices - Integrated circuits Part 6 analogue integrated circuits measuring methods Sec 1 general
36	IS 12970 (Part 6/Sec 2):1992 Reviewed In : 2018	Semiconductor devices - Integrated circuits Part 6 analogue integrated circuits measuring methods Sec 2 linear amplifiers
37	IS 12970 (Part 6/Sec 3):1992 Reviewed In : 2018	SemicOnductor devices integrated circuits Part 6 analogue integrated circuits measuring methods Sec 3 voltage regulators
38	IS 12970 (Part 6/Sec 4):1992 Reviewed In : 2018	Semiconductor devices - Integrated circuits Part 6 analogue integrated circuits - Measuring methods Sec 4 analogue signal switching circuits
39	IS 1301:1958	Code of safety requirements for electronic mains-operated audio amplifiers incorporated in IS 616
40	IS 1302:1958	Methods of measurements on audio amplifiers incorporated in IS 9302 Part 2
41	IS 13342:2001 ISO 1185 Reviewed In : 2008	Magnetic Oxide Cores ETD - Cores Intended for use in Power Supply Applications - Dimensions
42	IS 13504:1992 Reviewed In : 2020 IEC 60440: 1973	Method of measurement of non - Linearity in resistors
43	IS 13669:1993 IEC 249-3-3 Reviewed In : 2008	Permanent polymer coating materials solder-resist for use in the manufacture of printed circuits
44	IS 1490:1959	Recommendations for minimum performance requirements of mains-operated public address amplifiers incorporated in IS 10426
45	IS 14901 (Part 4):2016 IEC 60747-4	Semiconductor Devices Discrete Devices Part 4 Microwave Diodes and Transistors
46	IS 14901 (Part 5/Sec 1):2010 IEC 60747-5: 2002 Reviewed In : 2014 IEC 60747-5: 2002	Semiconductor Devices - Discrete Devices and Integrated Circuits Part 5 Optoelectronic Devices Secton 1 General
47	IS 14924:2001 IEC 758 Reviewed In : 2008	Synthetic Quartz Crystal s and Guide to the Use
48	IS 15212:2002 IEC/PAS 62212 Reviewed In : 2008	Specification and Characterization Methods for Nonwoven E Glass Mat
49	IS 15213:2002	Specification and Characterization Methods for Nonwoven Para-Aramid Reinforcement

	IEC/PAS 62213 Reviewed In : 2008	
50	IS 15214:2002 IEC/PAS 62119 Reviewed In : 2008	Generic Requirements for Implementation of Product Manufacturing Description Data and Transfer Methodology
51	IS 15215:2002 IEC/PAS 62123 Reviewed In : 2008	Performance Guide Manual for Single- and Double-Sided Flexible Printed Wiring Boards
52	IS 15252:2002 IEC/PAS 62214 Reviewed In : 2008	Generic Performance Printed Boards
53	IS 15479:2004 IEC/PAS 62293 Reviewed In : 2019 IEC/PAS 62293	Qualification and performance specification for high density interconnect HDI layers or boards
54	IS 1819:1961	Recommendations for general requirements of public address amplifiers
55	IS 1885 (Part 6):1978 Reviewed In : 2014 IEC 60194	Electrotechnical vocabulary Part 6 printed circuits First Revision
56	IS 1885 (Part 7):2001 Reviewed In : 2017 IEC 60050-521	Electrotechnical vocabulary Part 7 semiconductor devices and integrated circuits Second Revision
57	IS 1885 (Part 45):1977 Reviewed In : 2023 IEC 60050-516	Electrotechnical vocabulary Part 45 capacitors
58	IS 1885 (Part 46):1977 Reviewed In : 2023 IEC 60050-516	Electrotechnical vocabulary Part 46 resistors
59	IS 2001:1968 Reviewed In : 2018	Specification for fixed silvered mica capacitors First Revision
60	IS 2032 (Part 8):1965 Reviewed In : 2023	Graphical symbols used in electrotechnology Part 8 semiconductor devices
61	IS 2032 (Part 17):1975 Reviewed In : 2011	Graphical symbols used in electrotechnology Part 17 Ferrite cores and magnetic storage matrices
62	IS 2032 (Part 24):1980 IEC 117-13 Reviewed In : 2011	Graphical symbols used in electrotechnology Part 24 Binary logic elements
63	IS 2748:1964	Methods of measurements on microphones
64	IS 2786 (Part 1):1978 Reviewed In : 2021	Specification for ceramic dielectric capacitors type 2 Part 1 general requirements and methods of test First Revision
65	IS 2786 (Part 2):1984 Reviewed In : 2023	Specification for ceramic dielectric capacitors type 2 Part 2 FCCG 01 and FCCG 02 capacitors
66	IS/QC 300200:2000 Reviewed In : 2021 IECQC 300200: 1982	Fixed capacitors for use in electronic equipment Part 15 sectional specification fixedtantalum capacitors with non - Solid or solid electrolyte
67	IS/QC 300300:1992 Reviewed In : 2021 IECQC 300300: 1985	Fixed capacitors for use in electronic equipment Sectional specification aluminium electrolytic capacitors with solid and non - Solid elecroyte
68	IS/QC 300400:1988 Reviewed In : 2018 IECQC 300400: 1982	Fixed capacitors for use in electronic equipment Sectional specification fixed metallized polyethylene Terephthalate film dielectric DC capacitors
69	IS/QC 300700:1994 Reviewed In : 2018 IECQC 300700: 1988	Fixed capacitors for use in electronic equipment Sectional specification for fixed capacitors of ceramic dielectric class 2
70	IS/QC 302401:1994 Reviewed In : 2018 IECQC 302401: 1993	Fixed capacitors for use in electronic equipment blank detail specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains assessment level D

71	IS 3641:1976	Methods of measurements on hearing aids
72	IS 3671 (Part 1):1980 Reviewed In : 2018	Specification for air dielectric variable tuning capacitors Part 1 tests and general requirements First Revision
73	IS 3700 (Part 7):1970 Reviewed In : 2023 IEC 60147-1	Essential ratings and characteristics of semiconductor devices Part 7 reverse blocking triode thyristors
74	IS 3715 (Part 4):1971 Reviewed In : 2018 IEC 60148: 1969	Letter symbols for semiconductor devices Part 4 thyristors First Revision
75	IS 3723 (Part 1):1978 Reviewed In : 2021	Specification for capacitors for radio interference suppression Part 1 general requirements and methods of tests First Revision
76	IS 3723 (Part 2):1983 Reviewed In : 2021	Specification for capacitors for radio interference suppression Part 2 type Fcrs 1
77	IS 3723 (Part 3):1983 Reviewed In : 2021	Specification for capacitors for radio interference suppression Part 3 type Fcrs 2
78	IS/QC 390000:1994 Reviewed In : 2018 IECQC 390000: 1991	Fixed film resistor networks for use in electronic equipment - Generic specification
79	IS/QC 390100:1993 Reviewed In : 2018 IECQC 390100: 1991	Fixed film resistor networks for use in electronic equipment Secal specification for film resistor networks of assessed quality on the basis of the capability approval procedure
80	IS/QC 390101:1993 Reviewed In : 2018 IECQC 390101: 1991	Fixed film resistor networks for use in electronic equipment blank detail specification for film resistor networks of assessed quality on the basis of the capAbility approval procedure - Assessment level e
81	IS 3931:1966	Sound level meters for the measurement of noise emitted by motor vehicles incorporated in IS 9779
82	IS 3932:1966	Sound level meters for general purpose use incorporated in IS 9779
83	IS/QC 400000:1988 Reviewed In : 2018 IECQC 400000: 1982	Fixed resistors for use in electronic equipment generic specification
84	IS/QC 400300:1992 Reviewed In : 2021 IECQC 400300: 1982	Fixed resistors for use in electronic equipment Sectional specification fixed precision resistors
85	IS/QC 400301:1992 Reviewed In : 2021 IECQC 400301: 1983	Fixed resistors for use in electronic equipment blank detail specification fixed precision resistors assessment level E
86	IS/QC 400402:1993 Reviewed In : 2018 IECQC 400402: 1983	Fixed resistors for use in electronic equipment - Blank detail specification - Fixed resistor networks with individually measurable resistors of either different resistance values or different rated dissipations assessment level E
87	IS/QC 410000:2000 Reviewed In : 2018 IECQC 410000: 1989	Potentiometers for use in electronic equipment Part 1 generic specification Sec 1 Scope
88	IS/QC 420101:1994 Reviewed In : 2018 IECQC 420101	Varistors for use in electronic equipment - Blank detail specification for silicon carbide surge suppression varistors assessment level E
89	IS 4317:1983 Reviewed In : 2021 IEC 60384-4	Specification for aluminium electrolytic capacitors with non - Solid electrolyte Second Revision
90	IS 4400 (Part 7):1971 Reviewed In : 2018 IEC 60147-2: 1963	Methods of measurements on semiconductor devices Part 7 reverse blocking triode thyristors
91	IS 4406:1967	General Requirements For Hearing Aids
92	IS 4411:1967 Reviewed In : 2021	Code for designation of semiconductor devices
93	IS 4482:1967	Hearing Aids

94	IS 4633:1968 Reviewed In : 2015	Fixed Metallized-paper Dielectric Capacitor for Direct Current
95	IS 5000 (Part 1):1969 Reviewed In : 2008	Dimensions of semiconductor devices Devices outline OD 1
96	IS 5000 (Part 4):1969 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 4
97	IS 5000 (Part 5):1969 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 5
98	IS 5000 (Part 6):1969 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD6
99	IS 5000 (Part 7):1969 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD7
100	IS 5000 (Part 8):1969 Reviewed In : 2008	Dimensions of Semiconductor Devices - Device Outline OD8
101	IS 5000 (Part 9):1986 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 9
102	IS 5000 (Part 10):1971 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD10
103	IS 5000 (Part 11):1971 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD11
104	IS 5000 (Part 12):1971 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 12
105	IS 5000 (Part 13):1971 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 13
106	IS 5000 (Part 14):1971 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD14
107	IS 5000 (Part 15):1973 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 15
108	IS 5000 (Part 16):1973 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD16
109	IS 5000 (Part 17):1974 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 17
110	IS 5000 (Part 18):1974 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD18
111	IS 5000 (Part 19):1974 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD19
112	IS 5000 (Part 20):1978 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD 20
113	IS 5000 (Part 21):1979 Reviewed In : 2008	Dimensions of Semiconductor Device Outline OD 21
114	IS 5000 (Part 23):1978 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 23
115	IS 5000 (Part 25):1978 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 25
116	IS 5000 (Part 26):1978 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 26
117	IS 5000 (Part 27):1978 Reviewed In : 2008	Dimensions of Semiconductor Device Outline OD 27
118	IS 5000 (Part 28):1978 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD 28
119	IS 5000 (Part 29):1979 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 29
120	IS 5000 (Part 31):1981 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD31
121	IS 5000 (Part 32):1981 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 32
122	IS 5000 (Part 33):1981 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 33
123	IS 5000 (Part 34):1981	Dimensions of Semiconductor Devices Device Outline OD34

	Reviewed In : 2008	
124	IS 5000 (Part 35):1981 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 35
125	IS 5000 (Part 36):1981 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 36
126	IS 5000 (Part 37):1982 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 37
127	IS 5000 (Part 38):1984 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD38
128	IS 5000 (Part 39):1986 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 39
129	IS 5000 (Part 40):1986 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD 40
130	IS 5000 (Part 41):1986 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD 41
131	IS 5000 (Part 42):1986 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 42
132	IS 5000 (Part 43):1986 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 43
133	IS 5000 (Part 44):1986 Reviewed In : 2008	Dimensions of Semiconductor Devices Device Outline OD44
134	IS 5000 (Part 45):1986 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 45
135	IS 5000 (Part 46):1986 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 46
136	IS 5000 (Part 47):1986 Reviewed In : 2008	Dimensions of semiconductor devices Device outline OD 47
137	IS 5001 (Part 2):1973 Reviewed In : 2015	Guide for preparation of drawings of semiconductor devices and integrated circuits Part 2 Integrated circuits
138	IS 5027:1969 Reviewed In : 2021 IEC 60195	Method of measurement of current noise generated in fixed resistors
139	IS 5469 (Part 1):1969 Reviewed In : 2020	Code of practice for the use of semiconductor junction devices Part 1 applicable to all devices
140	IS 5469 (Part 2):1973 Reviewed In : 2021	Code of practice for the use of semiconductor junction devices Part 2 diodes
141	IS 5469 (Part 3):1973 Reviewed In : 2021	Code of practice for the use of semiconductor junction devices Part 3 thyristors
142	IS 5475 (Part 1):1978 Reviewed In : 2015	Polystyrene Film Dielectric Capacitors - Part I General Requirements and Methods of Tests
143	IS 5475 (Part 2):1979 Reviewed In : 2023	Specification for polystyrene film dielectric capacitors Part 2 type FCPS 1
144	IS 5475 (Part 4):1985 Reviewed In : 2023	Specification for fixed polystyrene film dielectric capacitors Part 4 type FCPS - 3
145	IS 5786 (Part 1):2018 IEC 60115-1 : 2008 Reviewed In : 2021 IEC 60115-1 : 2008	Fixed resistors for use in electronic equipment Part 1 generic specification Second Revision
146	IS 5786 (Part 3):1982 Reviewed In : 2018	Specification for fixed resistors general purpose low power Part 3 resistors type FRLP 2 First Revision
147	IS 5786 (Part 4):1982 Reviewed In : 2018	Specification for fixed resistors general purpose low power Part 4 resistors type FRLP 3 First Revision
148	IS 5786 (Part 5):1982 Reviewed In : 2018	Specification for fixed resistors general purpose low power Part 5 resistors type FRLP 4 First Revision
149	IS 5786 (Part 6):1982 Reviewed In : 2018	Specification for fixed resistors general purposes low power Part 4 resistors type FRLP 5 First Revision
150	IS 5786 (Part 7):1982 Reviewed In : 2023	Specification for fixed resistors general purpose low power Part 7 resistor type frlp 6 First Revision
151	IS 5786 (Part 10):1982	Specification for fixed resistors general purpose low power Part 10 resistors type FRLP 9 First -

	Reviewed In : 2018	Revision
152	IS 5786 (Part 12):1982 Reviewed In : 2018	Specification for fixed resistors general purpose low power Part x11 resistors type FRLP 11
153	IS 590:1964 Reviewed In : 2021	Specification for fixed paper dielectric capacitors for dc Revised
154	IS 5921 (Part 1):1993 IEC 249-1 Reviewed In : 2008	Metal-clad base materials for printed circuits for use in electronic and telecommunication equipment Part 1 General requirements and test
155	IS 5921 (Part 2):1973 IEC 249-2 Reviewed In : 2008	Metal-Clad Base Material for Printed Circuits for Use in Electronic and Telecommunication Equipment - Part 2 Paper Phenolic Copper-Clad Laminated Sheet-PF-CP-CU Economic Grade
156	IS 5921 (Part 3):1978 IEC 249-2 Reviewed In : 2008	Metal-Clad Base Materials for Printed Circuits for Use in Electronic and Telecommunication Equipment - Part 3 Phenolic Cellulose Paper Copper-Clad Laminated Sheet PF-CP-Cu High Electric Grade
157	IS 5921 (Part 4):1987 IEC 249-2 Reviewed In : 2008	Metal-clad Base Materials for Printed Circuits for Use in Electronic and Telecommunication Equipment - Part 4 Phenolic Cellulose Paper Copper Clad Laminated Sheet of Defined Flammability
158	IS 5921 (Part 5):1987 IEC 249-2 Reviewed In : 2008	Metal Clad Base Materials for Printed Circuits for Use in Electronic and Telecommunication Equipment - Part 5 Epoxide Cellulose Paper Copper Clad Laminated Sheet of Defined Flammability vertical burning test
159	IS 5921 (Part 6):1987 IEC 249-2 Reviewed In : 2008	Metal Clad Base Materials for Use in Electronic and Telecommunication Equipment - Part 6 Epoxide Woven Glass Fabric Copper Clad Laminated Sheet General Purpose Grade
160	IS 5921 (Part 7):1987 IEC 249-2 Reviewed In : 2008	Metal Clad Base Materials for Printed Circuits for Use in Electronic and Telecommunication Equipment - Part 7 Epoxide Woven Glass Fabric Copper-Clad Laminated Sheet of Defined Flammability
161	IS 5921 (Part 8):1988 IEC 249-2 Reviewed In : 2008	Metal-clad Base Materials for Printed Circuits for Use in Electronic and Telecommunication Equipment - Part 8 Flexible Copper-clad Polyester PETP Film
162	IS 5921 (Part 9):1988 IEC 249-2 Reviewed In : 2008	Metal-Clad Base Materials for Printed Circuits for Use in Electronic and Telecommunication Equipment - Part 9 Epoxide Cellulose Paper Core Epoxide Glass Cloth Surfaces Copper-Clad Laminated Sheet of Defined Flammability
163	IS 5921 (Part 10):1988 IEC 249-2 Reviewed In : 2008	Metal clad base materials for printed circuits for use in electronic and telecommunication equipment Part 10 Epoxide non-woven glass reinforced woven copper-clad laminated sheet of defined flammability VBT
164	IS 5921 (Part 11):1988 IEC 249-2 Reviewed In : 2008	Metal clad base materials for printed circuits for use in electronic and telecommunication equipment Part 11 Thin epoxide woven glass fabric copper clad laminated sheet general purpose grade for use in the fabrication of multilay
165	IS 5921 (Part 12):1988 IEC 249-2 Reviewed In : 2008	Specification for Metal-Clad Base Materials for Printed Circuits for Use in Electronic and Telecommunication Equipment - Part 12 Thin Epoxide Woven Glass Fabric Copper-Clad Laminated Sheet of Defined Flammability for Use in Fabrication of Multilayer
166	IS 6098:1971	Methods of measurement of airborne noise emitted by rotating electrical machinery
167	IS 6553:1971 Reviewed In : 2015	Environmental requirements for semiconductor devices and integrated circuits
168	IS/QC 720100-12:2001 Reviewed In : 2020 IECQC 720100-12	Semiconductor devices Part 12 Seical specification for optoelectronic devices
169	IS 7405 (Part 1):1994 IEC 326-2 Reviewed In : 2008	printed wiring boards Part 1 General requirements and methods of test
170	IS 7405 (Part 2):1984 IEC 326-4 Reviewed In : 2008	printed wiring boards Part 2 Single and double sided printed boards with plain holes
171	IS 7412:1974 Reviewed In : 2015	Life testing of semiconductor devices
172	IS 7440 (Part 2):1974 Reviewed In : 2015	Essential ratings and characteristics of analogue integrated circuits Part 2 Telecommunication amplifiers audio video and multichannel
173	IS 7440 (Part 3/Sec 1):1976	Essential ratings and characteristics of analogue integrated circuits Part 3 Operational amplifier

	Reviewed In : 2015	Sec 1 Having two input and one output
174	IS 7440 (Part 3/Sec 2):1977 Reviewed In : 2015	Essential ratings and characteristics of analogue integrated circuits Part 3 Operational amplifier Sec 2 Having two input and two outputs
175	IS/QC 750102:1989 Reviewed In : 2017 IECQC 750102	Semiconductor devices - Discrete devices - Bipolar transistors blank detail specification for ambient - Rated bipolar transistors for low and high - Frequency amplification
176	IS/QC 750104:1993 Reviewed In : 2018 IECQC 750104	Semiconductor devices - Discrete devices - Bipolar transistors - Blank detail specification for bipolar transistors for switching applications
177	IS/QC 750105:1994 Reviewed In : 2018 IECQC 750105	Semiconductor devices - Discrete devices - Signal Including Switching and regulator diodes - Blank detail specification for voltage - Regulator diodes and voltage - Reference diodes excluding temperature - Compensated precision reference diodes
178	IS/QC 750107:1994 Reviewed In : 2018 IECQC 750107	Semiconductor devices - Discrete device - Bipolar transistors - Blank detail specification for case - Rated bipolar transistors for high - Frequency amplification
179	IS/QC 750108:1992 Reviewed In : 2018 IECQC 750108	Semiconductor devices - Discrete devices rectifier diodes blank detail specification for rectifier diodes Including Avalanche Rectifier Diodes ambient and case - Rated up to 100 a
180	IS/QC 750111:1994 Reviewed In : 2018 IECQC 750111	Semiconductor devices - Discrete devices Part 6 thyristors Sec 2 blank detail specification for bidirectional triode thyristors Triacs ambient or case - Rated up to 100 a
181	IS 7741 (Part 1):1975 IEC 268-5	Loudspeakers Part 1 - General requirements and tests
182	IS 7741 (Part 4):1977 Reviewed In : 1993	Loudspeakers Part 4 Loudspeakers for community radio receivers
183	IS 7748 (Part 1):1975 Reviewed In : 2018	Specification for variable capacitors Part 1 tests and general requirements
184	IS 8083:1976 Reviewed In : 2015	Dimensions of ceramic dielectric capacitors of the plate type
185	IS 8238:1976 Reviewed In : 2015	Guide for use of variable capacitors in electronic equipment
186	IS 8426:2001 IEC 60556 Reviewed In : 2008	Measuring Methods for Properties of Gyromagnetic Materials Intended for Application at Microwave Frequencies
187	IS 8507 (Part 1):1977 Reviewed In : 2021	Specification for fixed tantalum capacitors with solid electrolyte Part 1 general requirements and methods of tests
188	IS 8507 (Part 2/Sec 1):1981 Reviewed In : 2023	Specification for fixed insulated hermetically sealed tantalum capacitors with solid electrolyte Part 2 type FCST 1 Sec 1 polar
189	IS 8507 (Part 2/Sec 2):1982 Reviewed In : 2023	Specification for fixed insulated hermetically sealed tantalum capacitors with solid electrolyte Part 2 type FCST 1 Sec 2 non - Polar
190	IS 8507 (Part 3/Sec 1):1981 Reviewed In : 2023	Specification for fixed insulated hermetically sealed tantalum capacitors with solid electrolyte Part 3 type fcst 2 Sec 1 polar
191	IS 8507 (Part 3/Sec 2):1982 Reviewed In : 2023	Specification for fixed insulated hermetically sealed tantalum capacitors with sealed electrolyte Part 3 type fcst 2 Sec 2 non - Polar
192	IS 8507 (Part 4/Sec 1):1983 Reviewed In : 2023	Specification for fixed insulated hermetically sealed tantalum capacitors with solid electrolyte Part 4 type FCST 3 Sec 1 polar
193	IS 8872 (Part 2/Sec 1):1979 Reviewed In : 2018	Specification for variable resistors Part 2 general purpose Sec 1 type VRG
194	IS 8872 (Part 2/Sec 2):1979 Reviewed In : 2018	Specification for variable resistors Part 2 general purpose Sec 2 type VRG 2C
195	IS 8872 (Part 2/Sec 3):1979 Reviewed In : 2018	Specification for variable resistors Part 2 general purpose Sec 3 type VRG3C
196	IS 8872 (Part 2/Sec 4):1979 Reviewed In : 2018	Specification for variable resistors Part 2 general purpose Sec 4 type VRG4P
197	IS 8872 (Part 2/Sec 5):1980 Reviewed In : 2018	Specification for variable resistors Part 2 general purpose Sec 5 type VRG 5C
198	IS 8872 (Part 2/Sec 6):1980 Reviewed In : 2018	Specification for variable resistors Part 2 general purpose Sec 6 type VRG 6C

199	IS 8872 (Part 3/Sec 1):1979 Reviewed In : 2018	Specification for variable resistors Part 3 precision Sec 1 type VRP 1P
200	IS 8872 (Part 3/Sec 2):1979 Reviewed In : 2018	Specification for variable resistors Part 3 precision Sec 2 type VRP 1P
201	IS 8872 (Part 4/Sec 1):1980 Reviewed In : 2021	Specification for variable resistors Part 4 preset Sec 1 type VRT 1
202	IS 8872 (Part 4/Sec 2):1983 Reviewed In : 2018	Specification for variable resistors Part 4 presents Sec 2 type VRT 2P
203	IS 8872 (Part 4/Sec 3):1982 Reviewed In : 2018	Specification for variable resistors Part 4 presets Sec 3 type VRT 3
204	IS 8872 (Part 4/Sec 4):1984 Reviewed In : 2018	Specification for variable resistors Part 4 preset Sec 4 type VRT 4 P
205	IS 8872 (Part 4/Sec 5):1984 Reviewed In : 2018	Specification for variable resistors Part 4 preset Sec 5 type VRT 5 P
206	IS 8909 (Part 1):1978 Reviewed In : 2015	Fixed Resistors General Purpose Power - Part I General Requirements and Methods of Tests
207	IS 8909 (Part 2):1978 Reviewed In : 2021	Specification for fixed resistors general purpose power Part 2 type FRP1
208	IS 8909 (Part 3):1978 Reviewed In : 2021	Specification for fixed resistors general purpose power Part 3 type FRP 2
209	IS 8909 (Part 4):1978 Reviewed In : 2021	Specification for fixed resistors general purpose power Part 4 type FRP 3
210	IS 8909 (Part 5):1978 Reviewed In : 2021	Specification for fixed resistors general purpose power Part 5 type FRP 4
211	IS 8943:1978 Reviewed In : 2020 IEC 60321: 1970	Guide to the design and use of components intended for mounting on boards with printed wiring and printed circuits
212	IS 9000 (Part 18/Sec 13):1981 Reviewed In : 2021	Basic environmental testing procedures for electronic and electrical items Part 18 solderABILITY test
213	IS 9001 (Part 9):1981 Reviewed In : 2021	Guidance for environmental testing Part 9 solderABILITY and resistance to soldering heat
214	IS 9256 (Part 2):1979 Reviewed In : 2021	Specification for fixed metallized polyester film dielectric capacitors Part 2 type FCPM 1
215	IS 9256 (Part 3):1979 Reviewed In : 2021	Specification for fixed metallized polyester film dielectric capacitors Part 3 type FCPM 2
216	IS 9302 (Part 1):1979 IEC 268-2 & 1, 1A & 1B Reviewed In : 2001	Characteristics and methods of measurements for sound system equipment Part 1 General
217	IS 9302 (Part 2):1979 IEC 60368-3 Reviewed In : 2001	Characteristics and methods of measurements for sound system equipment Part 2 Amplifiers
218	IS 9302 (Part 3):1981 Reviewed In : 2001	Characteristics and methods of measurements for sound system equipment Part 3 Microphones
219	IS 9302 (Part 4):1993 Reviewed In : 2002	Characteristics and methods of measurements for sound systems equipment Part 4 Loudspeaker
220	IS 9302 (Part 6):1986 IEC 60268-7 Reviewed In : 2001	Characteristics and methods of measurements for sound system equipment Part 6 Headphones and head sets
221	IS 9302 (Part 7):1987 IEC 60268-8 Reviewed In : 2005	Characteristics and methods of measurements for sound system equipment Part 7 Automatic gain control devices
222	IS 9302 (Part 10):1980 IEC 60268-15 Reviewed In : 2001	Characteristics and methods of measurements for sound system equipment Part 10 Preferred matching values for the inter-connection of sound system components
223	IS 9414 (Part 1/Sec 1):1979 Reviewed In : 2021	Detail specification for digital integrated circuits Part 1 nand gate TTL Sec 1 single 8 input positive
224	IS 9414 (Part 1/Sec 2):1979 Reviewed In : 2021	Detail specification for digital integrated circuits Part 1 nand gate TTL Sec 2 dual 4 input positive

225	IS 9414 (Part 1/Sec 3):1979 Reviewed In : 2021	Detail specification for digital integrated circuits Part 1 nand gate TTL Sec 3 triple 3 input positive
226	IS 9414 (Part 1/Sec 4):1979 Reviewed In : 2021	Detail specification for digital integrated circuits Part i nand gate TTL Sec 4 quad 2 input positive
227	IS 9437 (Part 1):1979 Reviewed In : 2021 IEC 60115-5: 1978	Specification for fixed precision resistors Part 1 general requirements and methods of test
228	IS 9437 (Part 2):1980 Reviewed In : 2021	Specification for fixed precision resistors Part 2 type FRPR 1
229	IS 9437 (Part 3):1980 Reviewed In : 2021	Specification for fixed precision resistors indian standard Part 3 type FRPR 2
230	IS 9437 (Part 4):1980 Reviewed In : 2021	Specification for fixed precision resistors Part 4 type FRPR 3
231	IS 9470:1979 Reviewed In : 2018 IEC 60115-1 : 2008	Method of test for the usABILITY of resistors under pulse conditions
232	IS 9501 (Part 1):1980 Reviewed In : 2018	Methods of measurement of electrical characteristics of microcircuits Part 1 digital micro circuits
233	IS 9501 (Part 2):1980 Reviewed In : 2018	Methods of measurement of electrical characteristics of microcircuits Part 2 analogue microcircuits
234	IS 9512:1980 Reviewed In : 2021	Guidance for pulse testing of resistors
235	IS 9593 (Part 1):1980 Reviewed In : 2018 IEC 60418-2: 1976	Specification for plastic film dielectric variable tuning capacitors grade 2 Part 1 tests and general requirements
236	IS 9596:1981 Reviewed In : 2021	General requirements and classification of tests for micro circuits
237	IS 9614 (Part 1):1980 Reviewed In : 2021	Specification for fixed high - Meg resistors Part 1 type FRHM 1
238	IS 9614 (Part 2):1980 Reviewed In : 2021	Specification for fixed high - Meg resistors Part 2 type FRHM 2
239	IS 9614 (Part 3):1980 Reviewed In : 2021	Specification for fixed high - Meg resistors Part 3 type FRHM 3
240	IS 9638 (Part 2):1984 Reviewed In : 2021	Specification for fixed polyester film dielectric capacitors for direct current Part 2 type FCPE 1
241	IS 9638 (Part 3):1985 Reviewed In : 2021	Specifacaton for fixed polyester film dielectric capacitors for direct current Part 3 type FCPE 2
242	IS 9638 (Part 4):1984 Reviewed In : 2021	Specification for fixed polyester film dielectric capacitors for direct current Part 4 type FCPE 3
243	IS 9779:1981 IEC 60651 Reviewed In : 2001	Sound Level Meters
244	IS 9807:1981 Reviewed In : 2018 IEC 60147-4	Life testing of digital microcircuits
245	IS 9816:1981 Reviewed In : 2021	General requirements and classification of tests for semiconductor devices

Annexure-II :List of Indian Product Standards

SI. No.	IS No. & Year	Title
1	IS/QC 001001:2000 Reviewed In : 2024 IECQC 001001	IEC quality assessment system for electronic components IECQ - Basic rules First Revision
2	IS/QC 001002-2:2000 Reviewed In : 2024 IECQC 001002-2: 1998	IEC quality assessment system for electronic components IECQ - Rules of procedure Part 2 Documentation First Revision
3	IS 12970 (Part 1):2010 Reviewed In : 2021 IEC	Semiconductor devices integrated circuits Part 1 general

60748-1:2002		
4	IS 12970 (Part 2):2021 IEC 60748-2: 1997 Reviewed In : 2024 ISO 20252: 2019	Semiconductor devices - Integrated circuits Part 2 Digital integrated circuits essential ratings and characteristics Sec 1 General
5	IS 12970 (Part 3):2021 IEC 60748-3: 1994 ISO 20488:2018	Semiconductor devices Integrated circuits Part 3 Analogue integrated circuits Superseding 1 IS 12970Part 5Sec 1 1991 2 IS 12970Part 5Sec 2 1992 3 IS 12970Part 5Sec 3 1992 4 IS 12970Part 5Sec 4 1992 5 IS 12970Part 5Sec 5 1993 6 IS 12970Part 5Sec
6	IS 13247 (Part 1):2021 IEC 60939-1: 2010 ISO 3823-2:2003	Passive filter units for electromagnetic interference suppression Part 1 Generic specification First Revision and Superseding 1 IS 3723Part 1 1978 2 IS 3723Part 2 1983 and 3 IS 3723Part 3 1983
7	IS 13247 (Part 2):2021 IEC 60939-2:2005 ISO 21363 : 2020	Passive filter units for electromagnetic interference suppression Part 2 Sectional specification Passive filter units for which safety tests are appropriate Test methods and general requirements First Revision of IS 13247 Part 2
8	IS 14901 (Part 1):2010 IEC 60747-1: 2006 Reviewed In : 2022 IEC 60747-1: 2006	Semiconductor devices - Discrete devices and integrated circuits Part 1 general First Revision
9	IS 14901 (Part 2):2020 IEC 60747-2: 2016 IEC 60747-2 : 2016	Semiconductor Devices Part 2 Discrete Devices Rectifier Diodes First Revision
10	IS 14901 (Part 5):2004 IEC 60747-5 Reviewed In : 2021 IEC 60747-5:1992	Semiconductor devices - Discrete devices and integrated circuits Part 5 optoelectronic devices
11	IS 14901 (Part 7):2020 IEC 60747-7 : 2010 IEC 60747-7 : 2010	Semiconductor Devices Discrete Devices Part 7 Bipolar Transistors First Revision
12	IS 14901 (Part 8):2020 IEC 60747-8 : 2010 IEC 60747-8 : 2010	Semiconductor Devices Discrete Devices Part 8 Field-Effect Transistors Second Revision
13	IS 15866 (Part 1):2010 IEC 60938-1:2006 Reviewed In : 2021 IEC 60938-1:2006	Fixed inductors for electromagnetic interference suppression Part 1 generic specification
14	IS/QC 300000:1988 Reviewed In : 2021 IECQC 300000:1982	Fixed capacitors for use in electronic equipment generic specification
15	IS/QC 300100:1988 Reviewed In : 2021 IECQC 300100: 1982	Fixed capacitors for use in electronic equipment Sectional specification fixed polyethersylene - Terephthalate film dielectric metal foil DC capacitor
16	IS/QC 300201:2000 Reviewed In : 2021 IECQC 300201: 1984	Fixed capacitors for use in electronic equipment Part 15 blank detail specification fixed tantalum capacitors with solid electrolyte and porous anode assessment level E
17	IS/QC 300301:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 300301: 1985	Fixed capacitors for use in electronic equipment blank detail specification aluminium electrolytic capacitors with non - Solid electrolyte assessment level E
18	IS/QC 300401:1988 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 300401: 1982	Fixed capacitors for use in electronic equipment blank detail specification fixed metallized polyethylene - Terephthalate film dielectric D C capacitors assessment level e
19	IS/QC 300600:1993 Reviewed In : 2021 IECQC 300600: 1988	Fixed capacitors for use in electronic equipment - Sectional specification for fixed capacitors of ceramic dielectric class 1
20	IS/QC 300601:1993 Reviewed In : 2021	Fixed capacitors for use in electronic equipment blank detail specification for fixed capacitors of ceramic dielectric class 1 assessment level E

	Reaffirmed but not taken up for revision IECQC 300601: 1988	
21	IS/QC 300701:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 300701: 1988	Fixed Capacitors for Use in Electronic Equipment Sectional Fixed Capacitors of Ceramic Dielectric Class 2
22	IS/QC 300800:1994 Reviewed In : 2020 IECQC 300800: 1989	Fixed capacitors for use in electronic equipment Sectional specification for fixed tantalum chip capacitors
23	IS/QC 300801:1993 Reviewed In : 2020 Reaffirmed but not taken up for revision IECQC 300801	Fixed capacitors for use in electronic equipment blank detail specification for fixed tantalum chip capacitors assessment level E
24	IS/QC 301200:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 301200: 1982	Fixed capacitors for use in electronic equipment Sectional specification for fixed metallized polypropylene film dielectric D C capacitors
25	IS/QC 301201:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 301201: 1982	Fixed capacitors for use in electronic equipment - Blank detail specification for fixed metallized polypropylene film dielectric D C capacitors - Assessment level e
26	IS/QC 301301:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 301301: 1987	Fixed capacitors for use in electronic equipment blank detail specification for fixed metallized polypropylene film dielectric A C and pulse capacitors assessment level E
27	IS/QC 301800:2001 Reviewed In : 2020 IECQC 301800: 1991	Fixed capacitors for use in electronic equipment Part 13 Secal specification fixed polypropylene film dielectric metal foil D C capacitors Sec one - General
28	IS/QC 301801:2001 Reviewed In : 2020 IECQC 301801: 1991	Fixed capacitors for use in electronic equipment Part 13 blank detail specification fixed polypropylene film dielectric metal foil D C capacitors assessment level E
29	IS/QC 302400:1994 Reviewed In : 2018 IECQC 302400: 1993	Fixed capacitors for use in electronic equipment Sectional specification for fixed capacitors for electromagnetic interference suppression and connection to the supply mains
30	IS/QC 400100:1988 Reviewed In : 2021 IECQC 400100: 1982	Fixed resistors for use in electronic equipment Sectional specification fixed low - Power non - Wire wound resistors
31	IS/QC 400101:1988 Reviewed In : 2021 IECQC 400101: 1982	Fixed restors for use in electronic equipment blank detail specification fixed low - Power non - Wirewound resistors assessment level E
32	IS/QC 400200:1992 Reviewed In : 2021 IECQC 400200: 1982	Fixed resistors for use in electronic equipment Sectional specification fixed power resistors
33	IS/QC 400400:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400400: 1983	Fixed resistors for use in electronic equipment - Sectional specification for fixed resistor networks with individually measurable resistors
34	IS/QC 400401:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400401: 1983	Fixed resistors for use in electronic equipment - Blank detail specification - Fixed resistor networks with individually measurable resistors all of equal value and equal dissipation assessment level E
35	IS/QC 400500:1993	Fixed resistors for use in electronic equipment - Sectional specification for fixed resistor networks

	Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400500: 1984	in which not all resistors are individually measurable
36	IS/QC 400501:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400501: 1984	Fixed resistors for use in electronic equipment - Blank detail specification for fixed resistors networks in which not all resistors are individually measurable - Assessment level E
37	IS/QC 400600:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400600: 1989	Fixed resistors for use in electronic equipment Sectional specification for fixed chip resistors
38	IS/QC 400601:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 400601: 1989	Fixed resistors for use in electronic equipment blank detail specification for fixed chip resistors assessment level E
39	IS/QC 410100:1992 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 410100: 1989	Potentiometers for use in electronic equipment Sectional specification lead - Screw actuated and rotary preset potentiometers
40	IS/QC 410101:1992 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 410101	Potentiometers for Use in Electronic Equipment Blank Detail Specification Lead-Screw Actuated and Rotary Preset Potentiometers Assessment Level E
41	IS/QC 420000:1994 Reviewed In : 2023 IECQC 420000	Varistors for use in electronic equipment - Generic specification
42	IS/QC 420100:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 420100	Varistors for use in electronic equipment -Sectional specification for surge suppression varistors
43	IS/QC 420102:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 420102	Varistors for use in electronic equipment - Blank detail specification for zinc oxide surge suppression varistors - Assessment level E
44	IS/QC 440000:1994 Reviewed In : 2018 IECQC 440000	Directly heated positive step function temperature coefficient thermistors - Generic specification
45	IS/QC 440001:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 440001	Directly heated positive step function temperature coefficient thermistors - Blank detail specification - Assessment level E
46	IS/IEC 60115-2:2023 IEC 60115-2: 2023	Fixed resistors for use in electronic equipment Part 2 Sectional specification Low-power film resistors with leads for through-hole assembly on circuit boards THT
47	IS/IEC 60384-4:2016 IEC 60384-4: 2016	Fixed capacitors for use in electronic equipment Part 4 Sectional specification Fixed aluminium electrolytic capacitors with solid MnO ₂ and non-solid electrolyte Superseding IS 4317 1983 and ISQC 300300 1992
48	IS/IEC 60384-9:2015 IEC 60384-9: 2015	Fixed capacitors for use in electronic equipment Part 9 Sectional specification Fixed capacitors of ceramic dielectric Class 2 Superseding IS 2786 Part 1 1978 and ISQC 300700 1994
49	IS/IEC 60384-15:2017 IEC 60384-15: 2017	Fixed capacitors for use in electronic equipment Part 15 Sectional specification Fixed tantalum capacitors with non-solid or solid electrolyte
50	IS/IEC 60384-141-1):2016	Fixed capacitors for use in electronic equipment Part 14 Blank detail specification Fixed

	IEC 60384-14-1: 2016 ISO 14952-1 : 2003	capacitors for electromagnetic interference suppression and connection to the supply mains Section 1 Assessment level DZ Superseding ISQC 302401 1994
51	IS/IEC 62326-1:2002 IEC 62326-1 : 2002 Reviewed In : 2024 IEC 62326-1 : 2002	Printed Boards Part 1 Generic specification
52	IS/IEC 62326-20:2016 IEC 62326-20 : 2016 Reviewed In : 2024 IEC 62326-20 : 2016	Printed Boards Part 20 Printed Circuit Boards for High-Brightness LEDs
53	IS 7305:2018 IEC 60384-1 : 2016 Reviewed In : 2021 IEC 60384-1:2016	Fixed capacitors for use in electronic equipment - Generic specification Second Revision
54	IS/QC 760000:1994 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 760000	Semiconductor devices - Integrated circuits - Generic specification for film integrated circuits and hybrid film integrated circuits
55	IS/QC 760100:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 760100	Semiconductor devices - Integrated circuits - Sectional specification for film integrated circuits and hybrid film integrated circuits on the basis of qualification approval procedure
56	IS/QC 760101:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 760101	Semiconductor devices - Integrated circuits - Blank detail specification for film integrated circuits and hybrid film integrated circuits on the basis of qualification approval procedure
57	IS/QC 760200:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 760200	Semiconductor devices - Integrated circuits - SectlOnal specification for film integrated circuits and hybrid film integrated circuits on the basis of the capability approval procedures
58	IS/QC 760201:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 760201	Semiconductor devices - Integrated circuits - Blank detail specification for film integrated circuits and hybrid film integrated circuits on the basis of the capability approval procedures
59	IS/QC 790130:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 790130	Semiconductor devices - Integrated circuits - Digital integrated circuits - Blank detail specification for HCMOS digital integrated circuits Series 54 74 HC 54 74 HCT 54 74 HCU
60	IS/QC 790131:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 790131	Semiconductor devices - Integrated circuits - Digital integrated circuits - Blank detail specification for complementary MOS digital integrated circuits Series 4000 Band 4000 Ub
61	IS/QC 790132:1995 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 790132	Semiconductor devices - Integrated circuits - Digital integrated circuits - Blank detail specification for bipolar monolithic digital integrated circuit gates Excluding Uncommitted Logic Arrays
62	IS/QC 790202:1993 Reviewed In : 2021 Reaffirmed but not taken up for revision IECQC 790202	Semiconductor devices - Integrated circuits - Analogue integrated circuits blank detail specification for monolithic integrated operational amplifiers
63	IS 9256 (Part 1):2019 IEC 60384-2 : 2011 Reviewed In : 2022 IEC 60384-2 :2011	Fixed capacitors for use in electronic equipment Part 1 Sectional specification - Fixed metallized polyethylene terephthalate film dielectric d c capacitors First Revision
64	IS 9638 (Part 1):1980 Reviewed In : 2021	Specification for fixed polyester film dielectric capacitors for direct current Part 1 general requirements and methods of tests